

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination TAKESUE ET AL.	
		Examiner David Buttner	Art Unit 1712	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0099120	07-2002	Takesue et al.	524/394
	B	US-6,315,915	11-2001	Hebert et al.	216/67
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-2002-336378	11-2002	JP	Ichikawa	---
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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